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# **General Multilayer Ceramic Capacitors**



MLCC is an electronic part that temporarily stores an electrical charge and the most prevalent type of capacitor today. New technologies have enabled the MLCC manufacturers to follow the trend dictated by smaller and smaller electronic devices such as Cellular telephones, Computers, DSC, DVC

## **General Features**

- Miniature Size
- Wide Capacitance and Voltage Range
- Tape & Reel for Surface Mount Assembly
- Low ESR

## **Applications**

- General Electronic Circuit

## Part Numbering

CL	<u>10</u>	<u>B</u>	<u>104</u>	K	<u>B</u>	<u>8</u>	N	N	N	<u>C</u>
Ú	2	6	4	6	6	Ø	8	9	<b>U</b>	<b>(i)</b>

- Samsung Multilayer Ceramic Capacitor
- 2 Size(mm)
- 3 Capacitance Temperature Characteristic
- 4 Nominal Capacitance
- **6** Capacitance Tolerance
- 6 Rated Voltage

- Thickness Option
- Product & Plating Method
- Samsung Control Code
- Reserved For Future Use
- Packaging Type

## **1** Samsung Multilayer Ceramic Capacitor

## 2 SIZE(mm)

Code	EIA CODE	Size(mm)
03	0201	0.6 × 0.3
05	0402	1.0 × 0.5
10	0603	1.6 × 0.8
21	0805	2.0 × 1.25
31	1206	3.2 × 1.6
32	1210	3.2 × 2.5
43	1812	4.5 × 3.2
55	2220	5.7 × 5.0





## **3** CAPACITANCE TEMPERATURE CHARACTERISTIC

Code		Temperatu	istics	Temperature Range	
С		COG	C△	0 ± 30 (ppm/ °C)	
Р		P2H	P△	-150±60	
R		R2H	R△	-220 ± 60	
S	Class	S2H	S△	-330 ± 60	-55 ~ +125℃
Т		T2H	T△	-470 ± 60	
U		U2J	U△	-750 ± 60	
L		S2L	S△	+350 ~ -1000	
Α		X5R	X5R	±15%	-55 ~ +85℃
В	Class II	X7R	X7R	±15%	-55 ~ +125℃
X	01055 11	X6S	X6S	±22%	-55 ~ +105℃
F		Y5V	Y5V	+22 ~ -82%	-30 ~ +85℃

### **\* Temperature Characteristic**

Temperature Characteristics	Below 2.0pF	2.2 ~ 3.9pF	Above 4.0pF	Above 10pF
СФ	COG	C0G	C0G	C0G
РΔ	-	P2J	P2H	P2H
R∆	-	R2J	R2H	R2H
SΔ	-	S2J	S2H	S2H
ΤΔ	-	T2J	T2H	T2H
UΔ	-	U2J	U2J	U2J

 $J:\pm 120 PPM/{^{\circ}\!\!\!\!C}\,,\, H:\pm 60 PPM/{^{\circ}\!\!\!\!C}\,,\, G:\pm 30 PPM/{^{\circ}\!\!\!\!C}$ 

## **4** NOMINAL CAPACITANCE

Nominal capacitance is identified by 3 digits.

The first and second digits identify the first and second significant figures of the capacitance.

The third digit identifies the multiplier. 'R' identifies a decimal point.

## Example

Code	Nominal Capacitance
1R5	1.5pF
103	10,000pF, 10nF, 0.01 μF
104	100,000pF, 100nF, 0.1 μ F





# CAPACITANCE TOLERANCE

Code	Tolerance	Nominal Capacitance
A	±0.05pF	
В	±0.1pF	
С	±0.25pF	Less than 10pF (Including 10pF)
D	± 0.5pF	(motioning Topi )
F	±1pF	
F	±1%	
G	±2%	
J	±5%	Mara than 1075
K	±10%	More than 10pF
М	±20%	
Z	+80, -20%	

# RATED VOLTAGE

Code	Rated Voltage	Code	Rated Voltage
R	4.0 V	D	200 V
Q	6.3V	E	250 V
P	10V	G	500 V
О	16V	Н	630 V
Α	25V	I	1,000V
L	35V	J	2,000V
В	50V	К	3,000V
С	100V		





## THICKNESS OPTION

Size	Code	Thickness(T)	Size	Code	Thickness(T)
0201(0603)	3	0.30±0.03		F	1.25±0.20
0402(1005)	5	0.50±0.05		н	1.6±0.20
0603(1608)	8	0.80±0.10	1812(4532)	I	2.0±0.20
	Α	0.65±0.10		J	2.5±0.20
	С	0.85±0.10		L	3.2±0.30
0805(2012)	F	1.25±0.10		F	1.25±0.20
	Q	1.25±0.15		н	1.6±0.20
	Υ	1.25±0.20	2220(5750)	I	2.0±0.20
	С	0.85±0.15		J	2.5±0.20
1206(3216)	F	1.25±0.15		L	3.2±0.30
	Н	1.6±0.20			
	F	1.25±0.20			
	Н	1.6±0.20			
1210(3225)	I	2.0±0.20			
	J	2.5±0.20			
	V	2.5±0.30			

## PRODUCT & PLATING METHOD

Code	Electrode	Termination	Plating Type
Α	Pd	Ag	Sn_100%
N	Ni	Cu	Sn_100%
G	Cu	Cu	Sn_100%

# SAMSUNG CONTROL CODE

Code	Description of the code	Code	Description of the code
Α	Array (2-element)	N	Normal
В	Array (4-element)	Р	Automotive
С	High - Q	L	LICC





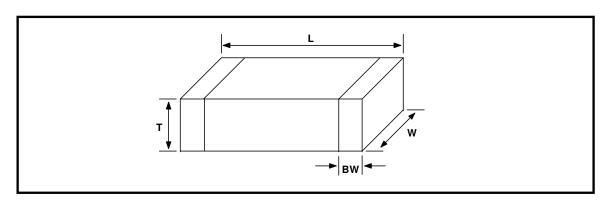
## **TRESERVED FOR FUTURE USE**

Code	Description of the code
N	Reserved for future use

## **1** PACKAGING TYPE

Code	Packaging Type	Code	Packaging Type
В	Bulk	F	Embossing 13" (10,000EA)
Р	Bulk Case	L	Paper 13" (15,000EA)
С	Paper 7"	0	Paper 10"
D	Paper 13" (10,000EA)	S	Embossing 10"
Е	Embossing 7"		

# APPEARANCE AND DIMENSION



CODE	EIA CODE		DIMENSION ( mm )							
CODE		L	W	T (MAX)	BW					
03	0201	0.6 ± 0.03	0.3 ± 0.03	0.33	0.15 ± 0.05					
05	0402	1.0 ± 0.05	0.5 ± 0.05	0.55	0.2 +0.15/-0.1					
10	0603	1.6 ± 0.1	0.8 ± 0.1 0.9		0.3 ± 0.2					
21	0805	2.0 ± 0.1	1.25 ± 0.1	1.35	0.5 +0.2/-0.3					
04	1000	3.2 ± 0.15	1.6 ± 0.15	1.40	0.5 +0.2/-0.3					
31	1206	$3.2 \pm 0.2$	1.6 ± 0.2	1.8	0.5 +0.3/-0.3					
20	1010	$3.2 \pm 0.3$	2.5 ± 0.2	2.7	0.6 + 0.2					
32	1210	$3.2 \pm 0.4$	2.5 ± 0.3	2.8	0.6 ± 0.3					
43	1812	4.5 ± 0.4	3.2 ± 0.3	3.5	0.8 ± 0.3					
55	2220	5.7 ± 0.4	5.0 ± 0.4	3.5	1.0 ± 0.3					





NO	ITE	М	PER	FORMANCE	TEST	CONDITION		
1	Appea	rance	No Abnormal Exterior	Appearance	Through Microscope(×10	)		
2	Insula Resist		Rated Voltage is below	Abnormal Exterior Appearance    1000		For 60 ~ 120 \$	Sec.	
3	Withsta	•	No Dielectric Breakdov Mechanical Breakdown	Class I: 300% of the Rated Voltage for 1~5 sec.  Class II: 250% of the Rated Voltage for 1~5 sec. is a with less than 50mA current				
					Capacitance	Frequency	Voltage	
		Class	Within the specifie	d tolerance	≤ 1,000 pF	1Mlz ±1 0%		
	Capacita   I				>1,000 pF	1 kHz ±1 0%	0.5 ~ 5 Vrms	
4	nce				Capacitance	Frequency	Voltage	
		Class	Within the specifi	ed tolerance	≤ 10 µF	1 kHz ±1 0%	1.0±0.2Vrms	
		П			>1 0 µF	120Hz±20%	0.5±0.1 Vrms	
			Capacitance ≥ 30pF :	Q ≥ 1.000	Capacitance	Frequency	Voltage	
5	Q	Class			≤ 1,000 pF	1Mb ±1 0%		
		. I I		: Capacitance )	>1,000 pF	1 kHz ±1 0%	0.5 ~ 5 Vrms	
			1. Characteristic : A()	X5R), B(X7R), X(X6S)	Capacitance	Frequency	Voltage	
			Rated Voltage	Spec	≤ 10 μF	1kHz ±1 0%	1.0±0.2Vrms	
			l <del></del>	· ·	>10 µF	120 Hz ± 20%	0.5±0.1 Vrms	
			<del> </del>	-	-			
			10V	0.05 max	-			
			6.3V	0.05 max/ 0.10max*1	*1. 0201 C≥0.022uF, 0	402 C≥0.22uF,	0603 C≥2.2uF,	
			2. Characteristic : F(\)	Y5V)	J 0805 C≥4.7uF, 1206 C≥10uF, 1210 C≥22uF, 1812 C≥47uF, 2220 C≥100uF, All Low Profile Capacitors (P.16).			
6	Tan δ	Class	Rated Voltage	Spec	[] '			
		П	50V	0.05 max, 0.07max*2	^3. 0402 C≥0.033uF, 00 All 0805, 1206 size		_	
			35V	0.07 max	*4 1210 C>6.8uF	1210 C- 0.8U	'	
			25V	0.05 max/ 0.07 max*³/ 0.09max*⁴	*5 0402 C≥0.22uF			
	16V		0.09 max/ 0.125max*5	0 All 1012 3126	*6 All 1812 size			
			10V	0.125 max/ 0.16max*6	]			
	6.3V			0.16max				





NO	ITC.	М		DEDECE	MANCE		TEST CONDITION		
NO	ITE	IVI		PERFOR	MANCE		TEST CONDITION		
							shall be measured by the steps		
			Characte	riation	Temp. Coefficient	shown in the	following table.		
			Characte	ristics	(PPM <sup>°</sup> C)	Step	Temp.(℃)		
			COC	à	0 ± 30	1	25 ± 2		
		Class	PH		-150 ± 60	2	Min. operating temp. $\pm$ 2		
		I	RH		-220 ± 60	3	25 ± 2		
			•	SH		-330 ± 60	4	Max. operating temp ± 2	
			TH		-470 ± 60	5	25 ± 2		
			UL		-750 ± 120	(1) Class I	20 – 2		
			SL		+350 ~ -1000	` '	Coefficient shall be calculated from		
	Temperature					the formula a			
7	Characteristics of Capacitance						$nt = \frac{C2 - C1}{C1 \times \triangle T} \times 10^6 \; [ppm/C]$		
						C1; Capacita	ance at step 3		
			Characte	eristics	Capacitance Change	C2: Capacita			
			Gnaraote	WILLI NO DIAS		△T: 60°C(=8	35 °C-25 °C )		
		Class	A(X5 B(X7	R)/ 'R)	± 15%	(2) CLASS II			
			X(X6	SS)	± 22%	Capacitance (	Change shall be calculated from the		
			F(Y5	iV)	+22% ~ -82%	formula as be			
							C1 × 100(%)		
						C1; Capacita	ance at step 3		
						C2: Capacita	ance at step 2 or 4		
						Apply 500g.f	* Pressure for 10 $\pm$ 1 sec.		
							* 200g.f for 0201 case size.		
	Adhesive	Stronath	No Indicati	on Of Paal	ing Shall Occur On The				
8	of Termi	•	Terminal E		ing Shail Occur On The		500g.f		
						Description Park	4		
		Apperance	No mecha	nical dam	nage shall occur.	Bending limit Test speed;			
							board at the limit point in 5 sec.,		
			Charact	teristics	Capacitance Change	Then measure	·		
					Within $\pm$ 5% or $\pm$ 0.				
			Clas	ss I	5 pF whichever is		20		
	Bending				larger		R=230		
9	9 Strength			A(X5R)/		50			
		Capacitance		B(X7R)/	Within ± 12.5%		<u> </u>		
				X(X6S)	12.070				
				7.(7.00)		<b>│                                    </b>	Bending limit		
			Class II			45±1	45±1		
				F(Y5V)	Within ± 30%				





NO	l I	EM		PERF	ORMANCE		TEST CON	IDITION		
		More Than 75% of the terminal surface is to Solder Sn-3Ag-0.5Cu								
			be soldere	d newly, So	metal part does not	Solder				
1.0			come out	or dissolve		Temp.	emp. 245±5 ℃ 235±5 ℃			
10	Solde	erability		// //			F	MA Type		
			<b>-</b>		/_//-	Dip Time	e 3±0.3 sec	5±0.5 sec.		
						Pre-heatir	ng at 80~120	°C for 10~30 sec.		
		Apperance	No mecha	anical dam	age shall occur.	Solder Ter	mperature: 270	±5℃		
			Charac	teristics	Capacitance Change		: 10±1 sec.			
					Within ±2.5% or			fully immersed and		
			Clas	s I	±0.25 pF whichever is	preheated as below :				
		Capacitance		A (VED)	larger	STEP	TEMP.(℃)	TIME(SEC.)		
				A(X5R)/ B(X7R)	Within ±7.5%	1	80~100	60		
			Class II	X(X6S)	Within ±15%	2	150~180	60		
	Resistance to			F	Within ±20%	Leave the	canacitor in an	nhient condition for		
11	Soldering heat		Capacitance ≥30pF : Q≥ 1000			Leave the capacitor in ambient condition for specified time* before measurement				
		Q (Olasa I.)		<b>&lt;30</b> pF	: Q≥ 400+20×C	* 24 ± 2 hours (Class I)				
		(Class I)			(C: Capacitance)	24 ± 2	hours (Class ${\mathbb I}$	)		
		Tan ∂	Within the	s specified	initial value					
		(Class II)	VVICINIT CITE	specified	initial value					
		Insulation	Within the	specified	initial value					
		Resistance								
		Withstanding Voltage	Within the	specified	initial value					
		Appearance	No mecha	anical dam	age shall occur.					
			Charact	eristics	Capacitance Change	1				
					Within ±2.5% or		citor shall be su	-		
			Clas	s I	±0.25 pF whichever is		_	a total amplitude of by from 10Hz to 55Hz		
		Capacitance			larger		to 10Hz In 1 m	-		
		·		A(X5R)/ B(X7R)	Within ±5%					
12	Vibration		Class	X(X6S)	Within ±10%	Repeat thi	s for 2hours ea	ich in 3 mutually		
	Test		1	F(Y5V)	Within ±20%	perpendicu	ılar directions			
		Q			<u>I</u>	-				
		(Class I)	Within the	specified	initial value					
		Tan $\delta$	Within the	ono sifis -l	initial value	1				
		(Class II)	vviunin the	specified	initial value					
		Insulation	Within the specified initial value							
		Resistance	vvitnin the	specified	initial value					





NO	ITE	М		PERFO	RMANCE	TEST CONDITION
		Appearance	No mechanic	al damage sha	Il occur.	Temperature : 40±2 ℃
				cteristics	Capacitance Change	Relative humidity : 90~95 %RH
				ss I	Within ±5.0% or ±0.5pF whichever is larger	Duration time : 500 +12/-0 hr.
		Capacitance	Class	A(X5R)/ B(X7R)/ X(X6S)	Within ±12.5%	Leave the capacitor in ambient condition for specified time* before measurement.
				F(Y5V)	Within ±30%	CLASS I : 24±2 Hr.
13	Humidity (Steady	Q CLASS I	10≤ Capacit	$\geq$ 30pF : Q $\geq$ tance <30 pF : C	350 2≥ 275 + 2.5×C 200 + 10×C (C: Capacitance)	CLASSII : 24±2 Hr.
	State)	Tan∂ CLASS II	1. Characterii 0.05max (16\ 0.075max (10\ 0.075max (6.3V excep 0.125max* (refer to Tab)	ot Table 1)	2. Characteristic : F(Y5V)  0.075max (25V and over)  0.1max (16V, C<1.0μF)  0.125max(16V, C≥ 1.0μF)  0.15max (10V)  0.195max (6.3V)	
		Insulation Resistance	1,000 MΩ or	50MΩ·μF whichev	ver is smaller.	
		Appearance	No mechanic	al damage sha	Il occur.	Applied Voltage : rated voltage
			Chara	cteristics	Capacitance Change Within ±5.0% or ±0.5pF	Temperature : 40±2 °C  Humidity : :90~95%RH  Duration Time : 500 +12/-0 Hr.
		Capacitance	Cla	ss I	whichever is larger	Charge/Discharge Current : 50mA max.
				A(X5R)/ B(X7R)/ X(X6S)	Within ±12.5% Within ±12.5% Within ±30%	Perform the initial measurement according to Note1.
			Class II		Within ±30%	
				F(Y5V)	Within ±30%	Perform the final measurement according to Note2.
14	Moisture Resistance	Q (Class I)	'	≥ 30 pF : Q≥ 2 <30 pF : Q≥ 10	00 + 10/3×C (C: Capacitance)	
		Tan δ (Class Ⅱ)	1. Characteristic: A(X5R), B(X7R) 0.05max (16V and over) 0.075max (10V) 0.075max (6.3V except Table 1) 0.125max* (refer to Table 1) X(X6S) 0.11max (6.3V and b		,	
		Resistance	500 MΩ or 25	MΩ·μF whicheve	r is smaller.	





NO	ITE	М		PER	FORMANCE		TEST CONDIT	ION		
		Appearance	No mechanio	cal damage	shall occur.	'''	oltage: 200%* of the	•		
			Charact	eristics	Capacitance Change		re : max. operating t ime : 1000 +48/-0 Hi	•		
					Within ±3% or ±0.3pF,	_	Charge/Discharge Current: 50mA max.			
			Class	3 I	Whichever is larger	* refer to	table(3): 150%/1009	of the rated		
		Capacitance		A(X5R)/ B(X7R)	Within ±12.5%	voltage	(abie(3) . 13078100	% OF THE FALEU		
			Class II	X(X6S)	Within ±25%	Perform th	e initial measurement	t according to		
				E2 (E) 0	Within ±30%	Note1 for	Class II			
				F(Y5V)	Within ±30%					
			Capacitance	≥30pF : C	Q ≥ 350	Perform th	e final measurement	according to		
		Q (Class I)	10≤ Capaci	tance <30 p	F : Q ≥ 275 + 2.5×C	Note2.	c ina measurement	according to		
	Llimb	(Class I)	Capacitance	< 10pF :Q	≥ 200 +10×C (C: Capacitance)					
15	High		1. Characteri	istic: A(X5F	R), 2. Characteristic : F(Y5V)					
15	Temperature Resistance			B(X7R)	)					
	nesistarice		0.05max		0.075max					
			(16V and o	•	(25V and over)					
			0.075max (1)	0V)	0.1max(16V, C<1.0μF)					
		Tan ∂	0.075max		0.125max(16V, C≥ 1.0 $\mu$ F)					
		(Class II)	(6.3V excep	ot Table 1)	0.15max (10V)					
			0.125max*		0.195max (6.3V)					
			(refer to Ta	ble 1)						
			X(X6S) 0.11	max (6.3V a	ind below)					
		Insulation Resistance	1,000 MΩ or	<b>50</b> MΩ.μF <b>wh</b> i	chever is smaller.					
		Appearance	No mechanic	cal damage	shall occur.	Capacitor	shall be subjected	d to 5 cycles.		
			Charact	eristics	Capacitance Change	Condition	for 1 cycle :			
			Class	. T	Within ±2.5% or ±0.25 pF	Step	Temp.(℃)	Time(min.)		
			Olass		Whichever is larger	_   1	Min. operating	30		
		Capacitance		A(X5R)/	\\/\text{ithin \pm 7 \text{ F9/}		temp.+0/-3			
			Class	B(X7R)/	Within ±7.5%	2	25	2~3		
16	Temperature		П	X(X6S)	Within ±15%	_   3	Max. operating	30		
	Cycle			F(Y5V)	Within ±20%	_	temp.+3/-0			
		Q	Within the s	necified initia	al value	4	25	2~3		
		(Class I)	vviumi the S		u vaiuc	Leave the	e capacitor in amb	ient condition		
		Tan $\delta$	VA (interior and in	n n niff = -l 1 · · · ·		for specif	ied time* before m	neasurement		
		(Class II)	Within the sp	peciriea initia	ai value	* 24 ± 2	hours (Class I)			
		Insulation		.,		24 $\pm$ 2 hours (Class II)				
		Resistance	Within the sp	pecified initia	ai value					





		Reco	ommended Sold	ering Method		
		Size	Temperature		Conc	lition
		inch (mm)	Characteristic	Capacitance	Flow	Reflow
		0201 (0603)	-	-	-	0
		0402 (1005)				
			Class I	=	0	0
		0603 (1608)	Class	C < 1μF	0	0
			Glass II	$C \geq 1\mu F$	-	0
	Recommended	0805 (2012)	Class I	=	0	0
18	Soldering Method		Class II	$C < 4.7 \mu F$	0	0
	By Size & Capacitance		01033 11	$C \geq 4.7 \mu F$	-	0
	2, 0.20 a capacitaco		Array	-	-	0
			Class I	=	0	0
		1206 (3216)	Class	C < 10μF	0	0
		1200 (3210)	Class II	C ≥ 10 <i>μ</i> F	-	0
			Array	-	-	0
		1210 (3225)				0
		1808 (4520)				0
		1812 (4532)	-	-	-	0
		2220 (5750)		Class II $C \ge 1\mu\Gamma$ Class I $C < 4.7\mu\Gamma$ Class II $C < 4.7\mu\Gamma$ Array $C < 4.7\mu\Gamma$ Class I $C < 10\mu\Gamma$ Class II $C < 10\mu\Gamma$		0

Note1. Initial Measurement For Class  $\ensuremath{\mathbb{I}}$ 

Perform the heat treatment at 150%+0/-10% for 1 hour. Then Leave the capacitor in ambient condition for  $48\pm4$  hours before measurement. Then perform the measurement.

#### Note2. Latter Measurement

### 1. CLASS I

Leave the capacitor in ambient condition for 24±2 hours before measurement

Then perform the measurement.

#### 2. Class ${\mathbb I}$

Perform the heat treatment at  $150\,^{\circ}\text{C} + 0/-10\,^{\circ}\text{C}$  for 1 hour. Then Leave the capacitor in ambient condition for  $48\pm4$  hours before measurement. Then perform the measurement.

\*Table1.

Tan δ	0.125max*
Class II A(X5R), B(X7R)	0201 C $\geq$ 0.022 $\mu$ F 0402 C $\geq$ 0.22 $\mu$ F 0603 C $\geq$ 2.2 $\mu$ F 0805 C $\geq$ 4.7 $\mu$ F 1206 C $\geq$ 10.0 $\mu$ F 1210 C $\geq$ 22.0 $\mu$ F 1812 C $\geq$ 47.0 $\mu$ F 2220 C $\geq$ 100.0 $\mu$ F All Low Profile Capacitors (P.16).

\*Table2.

High Tem	perature Resistance test
⊿C (Y5V)	± 30%
	0402 C $\geq$ 0.47 $\mu$ F
	0603 C ≥ 2.2μF
Class ∏	0805 C ≥ 4.7μF
F(Y5V)	1206 C ≥ 10.0 <i>μ</i> F
1 (134)	1210 C ≥ 22.0 <i>μ</i> F
	1812 C $\geq$ 47.0 $\mu$ F
	2220 C $\geq 100.0 \mu \text{F}$

\*Table3.

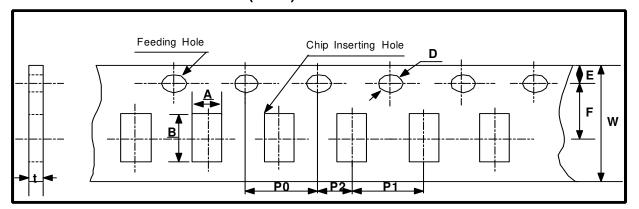
High Temperature Resistance test								
Applied Voltage	100% of the rated voltage	150% of the rated voltage						
Class II A(X5R), B(X7R), X(X6S), F(Y5V)	0201 C $\geq 0.1 \mu F$ 0402 C $\geq 1.0 \mu F$ 0603 C $\geq 4.7 \mu F$ 0805 C $\geq 22.0 \mu F$ 1206 C $\geq 47.0 \mu F$ 1210 C $\geq 100.0 \mu F$ All Low Profile Capacitors (P.16).	0201 C $\geq 0.022 \mu F$ 0402 C $\geq 0.47 \mu F$ 0603 C $\geq 22 \mu F$ 0805 C $\geq 4.7 \mu F$ 1206 C $\geq 10.0 \mu F$ 1210 C $\geq 22.0 \mu F$ 1812 C $\geq 47.0 \mu F$ 2220 C $\geq 100.0 \mu F$						





# **PACKAGING**

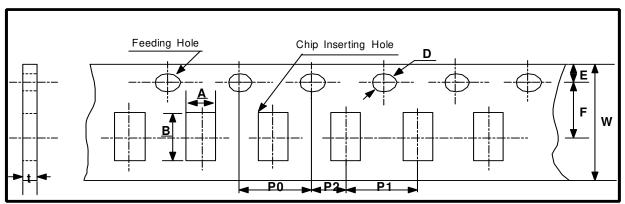
# ● CARDBOARD PAPER TAPE (4mm)



unit : mm

	mbol ype	Α	В	w	F	E	P1	P2	P0	D	t
D i m	0603 (1608)	1.1 ±0.2	1.9 ±0.2								
e n s	0805 (2012)	1.6 ±0.2	2.4 ±0.2	8.0 ±0.3	3.5 ±0.05	1.75 ±0.1	4.0 ±0.1	2.0 ±0.05	4.0 ±0.1	Ф1.5 +0.1/-0	1.1 Below
i o n	1206 (3216)	2.0 ±0.2	3.6 ±0.2								

## ● CARDBOARD PAPER TAPE (2mm)



unit: mm

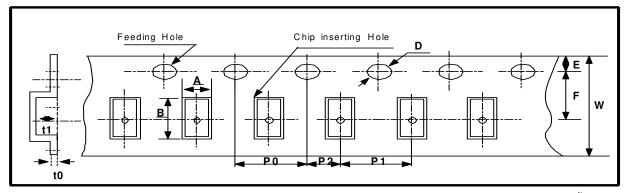
	ymbol Type	A	В	w	F	E	P1	P2	P0	D	t
D i m e	0201 (0603)	0.38 ±0.03	0.68 ±0.03	8.0	3.5	1.75	2.0	2.0	4.0	Ф1.5	0.37 ±0.03
n s i o n	0402 (1005)	0.62 ±0.04	1.12 ±0.04	±0.3	±0.05	±0.1	±0.05	±0.05	±0.1	+0.1/-0.03	0.6 ±0.05





# **PACKAGING**

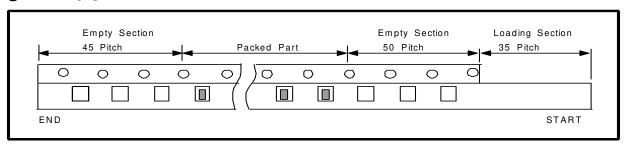
## **● EMBOSSED PLASTIC TAPE**



unit: mm

Sy	m bol	Α	В	w	F	Е	P1	P2	P0	D	t1	t0
Т	уре				·				. •			
	0805 (2012)	1.45 ±0.2	2.3 ±0.2									
D	1206 (3216)	1.9 ±0.2	3.5 ±0.2	8.0 ±0.3	3.5 ±0.05		4.0 ±0.1				2.5 max	
m e	1210 (3225)	2.9 ±0.2	3.7 ±0.2			1.75		2.0	4.0	Ф1.5 +0.1/-0		0.6
n s i	1808 (4520)	2.3 ±0.2	4.9 ±0.2			±0.1		±0.05	±0.1	+0.17-0		Below
o n	1812 (4532)	3.6 ±0.2	4.9 ±0.2	12.0 ±0.3	5.60 ±0.05		8.0 ±0.1				3.8 max	
	2220 (5750)	5.5 ±0.2	6.2 ±0.2									

## TAPING SIZE



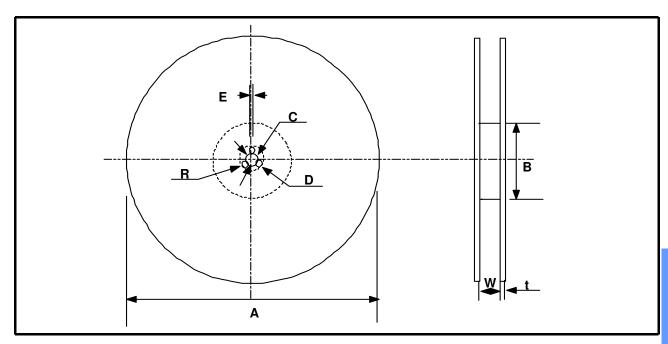
Type	Symbol	Size	Cardboard Paper Tape	Symbol	Size	Embossed Plastic Tape
		0201(0603)	10,000		All Size ≤3216 1210(3225),1808(4520) (t≤1.6mm)	2,000
7" Reel	С	0402(1005)	10,000	E	1210(3225)(t≥2.0 m m)	1,000
	ОТН	OTHERS	4,000		1808(4520)(t≥2.0 m m)	1,000
10" Reel	0	-	10,000	-	-	-
	D	0402(1005)	50,000		All Size ≤3216 1210(3225),1808(4520) (t<1.6mm)	10,000
		OTHERS	10,000		$1210(3225)(1.6 \le t < 2.0 \text{ m m}) \\ 1206(3216)(1.6 \le t)$	8,000
13" Reel		0603(1608)	10,000 or 15,000	F	1210(3225),1808(4520) (t≥2.0mm)	4,000
	L	0805(2012) (t≤0.85mm)	15,000 or 10,000(Option)		1812(4532)(t≤2.0 m m)	4,000
		1206(3216) (t≤0.85mm)	10,000		1812(4532)(t>2.0mm) 5750(2220)	2,000





# PACKAGING

## • REEL DIMENSION



unit: mm

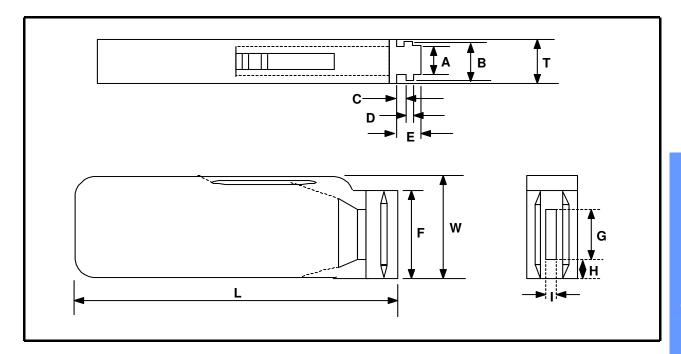
Symbol	Α	В	С	D	E	W	t	R
7" Reel	ф180+0/ -3	φ60+1/ -3	440 1 0 0	05   0.5	00105	0.14.5	1.2±0.2	1.0
13" Reel	ф330±2.0	φ80+1/ -3	φ13±0.3	25±0.5	2.0±0.5	9±1.5	2.2±0.2	1.0





## BULK CASE PACKAGING

- Bulk case packaging can reduce the stock space and transportation costs.
- The bulk feeding system can increase the productivity.
- It can eliminate the components loss.



unit: mm

Symbol	Α	В	Т	С	D	E
Dimension	6.8±0.1	8.8±0.1	12±0.1	1.5+0.1/-0	2+0/-0.1	3.0+0.2/-0

Symbol	F	W	G	Н	L	I
Dimension	31.5+0.2/-0	36+0/-0.2	19±0.35	7±0.35	110±0.7	5±0.35

## QUANTITY OF BULK CASE PACKAGING

unit : pcs

Ci	0400(1005)	0000(1000)	0805(	2012)
Size	0402(1005)	0603(1608)	T=0.65mm	T=0.85mm
Quantity	50,000	10,000 or 15,000	10,000	5,000 or 10,000

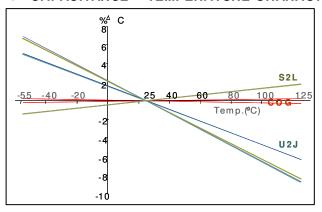


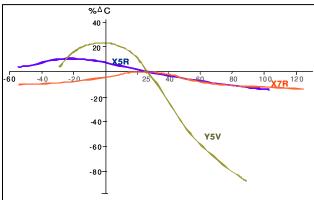


## **APPLICATION MANUAL**

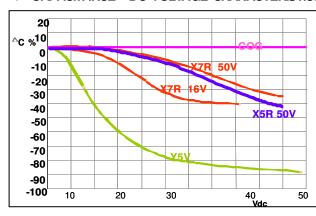
### • ELECTRICAL CHARACTERISTICS

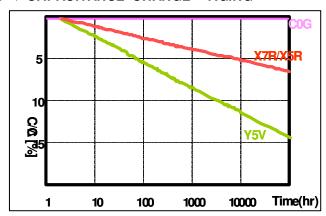
### ► CAPACITANCE - TEMPERATURE CHARACTERISTICS



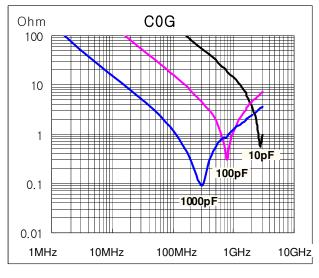


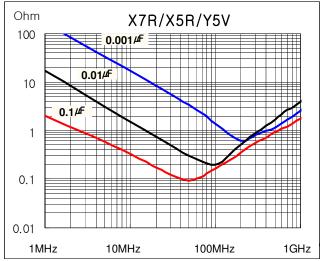
### ► CAPACITANCE - DC VOLTAGE CHARACTERISTICS ► CAPACITANCE CHANGE - AGING





### **▶ IMPEDANCE - FREQUENCY CHARACTERISTICS**









### STORAGE CONDITION

### ▶ Storage Environment

The electrical characteristics of MLCCs were degraded by the environment of high temperature or humidity. Therefore, the MLCCs shall be stored in the ambient temperature and the relative humidity of less than 40°C and 70%, respectively.

Guaranteed storage period is within 6 months from the outgoing date of delivery.

#### Corrosive Gases

Since the solderability of the end termination in MLCC was degraded by a chemical atmosphere such as chlorine, acid or sulfide gases, MLCCs must be avoid from these gases.

### ▶ Temperature Fluctuations

Since dew condensation may occur by the differences in temperature when the MLCCs are taken out of storage, it is important to maintain the temperature-controlled environment.

### DESIGN OF LAND PATTERN

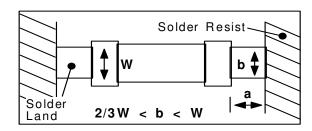
When designing printed circuit boards, the shape and size of the lands must allow for the proper amount of solder on the capacitor.

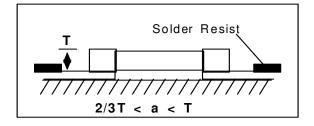
The amount of solder at the end terminations has a direct effect on the crack.

The crack in MLCC will be easily occurred by the tensile stress which was due to too much amount of solder. In contrast, if too little solder is applied, the termination strength will be insufficiently.

Use the following illustrations as guidelines for proper land design.

Recommendation of Land Shape and Size.









### ADHESIVES

When flow soldering the MLCCs, apply the adhesive in accordance with the following conditions.

### ► Requirements for Adhesives

They must have enough adhesion, so that, the chips will not fall off or move during the handling of the circuit board.

They must maintain their adhesive strength when exposed to soldering temperature.

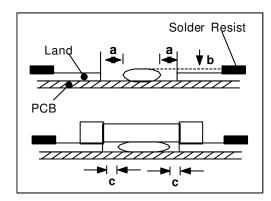
They should not spread or run when applied to the circuit board.

They should harden quickly. They should not corrode the circuit board or chip material.

They should be a good insulator. They should be non-toxic, and not produce harmful gases, nor be harmful when touched.

### Application Method

It is important to use the proper amount of adhesive. Too little and much adhesive will cause poor adhesion and overflow into the land, respectively.



		unit : mm
Туре	21	31
а	0.2 min	0.2 min
b	70~100 µm	70~100 µm
С	> 0	> 0

### Adhesive hardening Characteristics

To prevent oxidation of the terminations, the adhesive must harden at 160 ℃ or less, within 2 minutes or less.

### MOUNTING

### Mounting Head Pressure

Excessive pressure will cause crack to MLCCs. The pressure of nozzle will be 300g maximum during mounting.

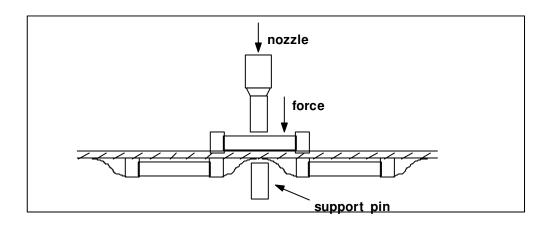




### ▶ Bending Stress

When double-sided circuit boards are used, MLCCs first are mounted and soldered onto one side of the board. When the MLCCs are mounted onto the other side,

it is important to support the board as shown in the illustration. If the circuit board is not supported, the crack occur to the ready-installed MLCCs by the bending stress.



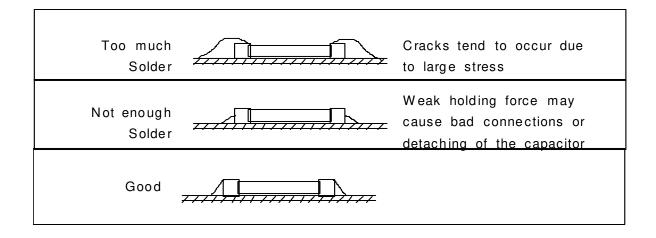
### ▶ Manual Soldering

Manual soldering can pose a great risk of creating thermal cracks in chip capacitors.

The hot soldering iron tip comes into direct contact with the end terminations, and operator's carelessness may cause the tip of the soldering iron to come into direct contact with the ceramic body of the capacitor.

Therefore the soldering iron must be handled carefully, and close attention must be paid to the selection of the soldering iron tip and to temperature control of the tip.

### Amount of Solder







## ▶ Cooling

Natural cooling using air is recommended. If the chips are dipped into solvent for cleaning, the temperature difference( $\triangle T$ ) must be less than 100  $^{\circ}$ C

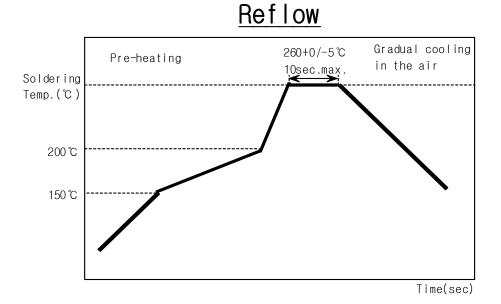
### ▶ Cleaning

If rosin flux is used, cleaning usually is unnecessary. When strongly activated flux is used, chlorine in the flux may dissolve into some types of cleaning fluids, thereby affecting the chip capacitors. This means that the cleaning fluid must be carefully selected, and should always be new.

## ▶ Notes for Separating Multiple, Shared PC Boards.

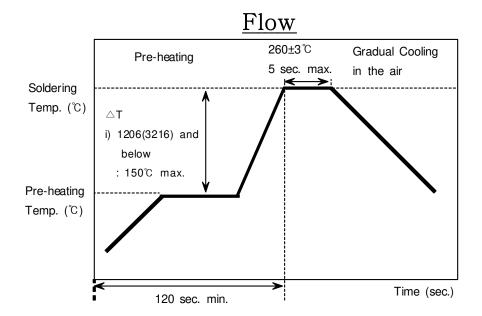
A multi-PC board is separated into many individual circuit boards after soldering has been completed. If the board is bent or distorted at the time of separation, cracks may occur in the chip capacitors. Carefully choose a separation method that minimizes the bending often circuit board.

## ► Recommended Soldering Profile









# Soldering Iron

Variation of Temp.	Soldering	Pre-heating	Soldering	Cooling
	Temp (℃)	Time (Sec)	Time(Sec)	Time(Sec)
△T≤130	300±10°Cmax	≥ 60	≤ 4	-

Condition of Iron facilities					
Wattage	Tip Diameter	Soldering Time			
20W Max	3mm Max	4 Sec Max			

<sup>\*</sup> Caution - Iron Tip Should Not Contact With Ceramic Body Directly.